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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re patent application of:

Clausen et al.

MMB Docket No. **1890-0335**

Application No. **10/559,697**

Filed: **December 6, 2005**

For: **Method for Reducing the Crest
Factor**

Examiner: **To be assigned**

Group Art Unit: **To be assigned**

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David R. Moorman

Name of person mailing Document or fee

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Signature

October 11, 2006

Date of Signature

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Pursuant to 37 CFR §1.56, Applicants hereby disclose the following reference(s)
regarding the above-identified patent application.

U.S. Patent

6,175,551 B1

6,529,925 B1

Inventor

Awater et al.

Schenk

Issue Date

Jan. 16, 2001

Mar. 4, 2003

U.S. Publication

2003/0026263 A1

2002/0159532 A1

2002/0196863 A1

2003/0043895 A1

Inventor

Taunton

Wight

Kaku et al.

Melsa

Publication Date

Feb. 6, 2003

Oct. 31, 2002

Dec. 26, 2002

Mar. 6, 2003

<u>Foreign References</u>	<u>Publication Date</u>	<u>Country</u>
DE 198 38 295 A1	Jun. 17, 1999	Germany
DE 198 50 642 A1	May 4, 2000	Germany
WO 03/026240 A2	Mar. 27, 2003	PCT
EP 0 725 510 A1	Aug. 7, 1996	Europe

Article

- 1) Henkel et al., "PAR Reduction Revisited: An Extension to Tellado's Method," International OFDM-Workshop, Sep. 17, 2001, pp. 1-6, (6 pages).

DE 198 38 295 A1, DE 198 50 642 A1, WO 03/026240 A2, US 2003/0026263 A1, and EP 0 725 510 A1 were cited in a German Examination Procedure (copy enclosed) dated Feb. 25, 2004 for German priority application DE 103 25 836.1 filed Jun. 6, 2003.

WO 03/026240 A2, the Henkel article, US 2002/0159532 A1, US 2002/0196863 A1, US 6175551 B1 and US 2003/0043895 A1 were cited in an International Search Report (copy enclosed) for corresponding application PCT/EP2004/006003.


An English language abstract is enclosed for DE 198 38 295 A1 and WO 03/026240 A2. US 6,529,925 B1 is an English language equivalent of DE 198 50 642 A1.

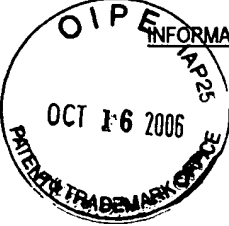
Pursuant to 37 C.F.R. § 1.97(b), this Information Disclosure Statement is being filed within three months after the filing date of the application or before the mailing of the first office action on the merits.

It is believed that no fees are due for the consideration of this Information Disclosure Statement. However, the Commissioner is hereby authorized to charge any deficiency or to credit any overpayment to Deposit Account No. 13-0014, but not to include any payment of issue fees.

October 11, 2006
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Respectfully Submitted,


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 <p>FORM PTO-1449 INFORMATION DISCLOSURE STATEMENT</p>	MMB DOCKET NO. 1890-0335	APPLICATION NO.: 10/559,697
	APPLICANT(S): Clausen et al.	
	FILING DATE: December 6, 2005	GROUP ART UNIT: TBD

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
	AA	6,175,551 B1	Jan. 16, 2001	Awater et al.			
	AB	6,529,925 B1	Mar. 4, 2003	Schenk			
	AC	2003/0026263 A1	Feb. 6, 2003	Taunton			
	AD	2002/0159532 A1	Oct. 31, 2002	Wight			
	AE	2002/0196863 A1	Dec. 26, 2002	Kaku et al.			
	AF	2003/0043895 A1	Mar. 6, 2003	Melsa			
	AG						
	AH						
	AI						
	AJ						
	AK						
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION
	AL	DE 198 38 295 A1	Jun. 17, 1999	Germany			Yes No
	AM	DE 198 50 642 A1	May 4, 2000	Germany			Yes No
	AN	WO 03/026240 A2	Mar. 27, 2003	PCT			Yes No
	AO	EP 0 725 510 A1	Aug. 7, 1996	Europe			Yes No
	AP						Yes No
OTHER (Including Author, Title, Date, Pertinent Pages, etc.)							
	AQ		Henkel et al., "PAR Reduction Revisited: An Extension to Tellado's Method," International OFDM-Workshop, Sep. 17, 2001, pp. 1-6, (6 pages).				
	AR						
	AS						
EXAMINER					DATE CONSIDERED		
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicants.							